

INFORMATION DISCLOSURE  
CITATION

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APPLICANT

GLASPER et al

FILING DATE

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SERIAL NO.

10/520,850

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2878



(Use several sheets if necessary)

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
TK	4,127,932	12/1978	Hartman et al			
TK	4,442,444	4/1984	Osaka			
TK	5,236,871	8/1993	Fossum et al			
TK	5,621,227	4/1997	Joshi			
TK	5,354,707	10/1994	Chapple-Sokol et al			
TK	4,689,305	8/1987	Stiffey et al			
TK	6,043,517	3/2000	Presting et al			
TK	5,796,118	8/1998	Morikawa et al			
TK	5,783,839	7/1998	Morikawa et al			
TK	5,144,381	9/1992	Furuyama et al			
TK	6,392,282	5/2002	Sahara et al			
TK	6,100,551	8/2000	Lee et al			
TK	6,417,504	7/2002	Kozlowski			
TK	4,491,802	1/1985	Uchida et al			
TK	2001/0002045 A1	5/2001	Fossum et al			
TK	5,483,200	1/1996	Okabayashi et al			
TK	6,407,442	6/2002	Inoue et al			
TK	6,107,619	8/2000	Cunningham et al			
TK	6,005,266	12/1999	Forrest et al			
TK						

## FOREIGN PATENT DOCUMENTS

	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
TK	0 540 235	5/1993	EP			
TK	2 202 624	9/1988	GB			
TK	0 967 656	12/1999	EP			
TK	10-190041	7/1998	JP			ABSTRACT

## OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

TK	J. Huppertz et al, "Fast CMOS Imaging With High Dynamic Range" Proc. 1997 IEEE Workshop on Charge-Coupled Devices and Advanced Image Sensors
TK	E. Fossum, "Image Capture Circuits in CMOS" 1997 International Symposium on VLSI Technology, Systems, and Applications
TK	N. Tu et al, "CMOS Active Pixel Image Sensor With Combined Linear and Logarithmic Mode Operation" Electrical and Computer Engineering, 1998, pages 754-757
TK	T. Delbruck et al, "Adaptive Photoreceptor With Wide Dynamic Range" Circuits and Systems, 1994, pages 339-342
TK	S.M. Sze VLSI Technology pp. 482-485
TK	Spinelli et al IEEE Transactions on Electron Devices, Vol. 44, No. 11, Nov. 1997 pp. 1931-1943 Physics and Numerical Simulation of Single Photon Avalanche Diodes
TK	Jackson et al Proc. IEEE 2001 Int. Conference on Microelectronic Test Structures, Vol. 14, March 2001 pp. 165-170 Process Monitoring and Defect Characterization of Single Photon Avalanche Diodes

/Tony Ko/

03/07/2007

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Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Initial this form with next communication to application.